Notice of References Cited Application/Control No. 10/565,797 Examiner Thien T. Mai Applicant(s)/Patent Under Reexamination PRAX ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

$\overline{}$					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,729,564 A	03-1988	Kuna et al.	463/9
*	В	US-4,604,065	08-1986	Frazer et al.	434/331
*	С	US-7,032,823	04-2006	Nojiri, Tadao	235/462.09
*	D	US-2002/0123297 A1	09-2002	Hornsby et al.	446/484
*	Е	US-2002/0117549	08-2002	Lee, Martin	235/462.45
*	F	US-6,997,773	02-2006	Dubois et al.	446/175
*	G	US-6,446,871	09-2002	Buckley et al.	235/472.03
*	Ι	US-7,164,811	01-2007	Nathanson et al.	382/313
*	I	US-6,148,331	11-2000	Parry, Rhys Evan	709/218
*	J	US-5,852,434	12-1998	Sekendur, Oral F.	345/179
*	K	US-5,661,506	08-1997	Lazzouni et al.	345/179
*	L	US-5,640,193	06-1997	Wellner, Pierre David	725/100
*	М	US-2006/0154559	07-2006	Yoshida, Kenji	446/297

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	EP 281257 A1	09-1988	European Patent	FRAZER et al.	
	0	WO 9528695 A1	10-1995	World Intellect	POPOVICH, MILAN MOMCILD	
	Ρ					
	Ø					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.